

# Maskless photolithography with the MLA150

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The MLA 150 is a new generation laser writer aiming to provide a different and faster approach to standard photolithography. The embedded technology allows quick configuration, sub micrometric alignment and fast exposure of CAD designs within a few minutes, without the need to produce a photomask. This is a presentation of resists that have been tested with the MLA150 along several SEM illustrations.

Resist	Film thick. [um]	Dose [mJ/cm <sup>2</sup> ]	Defoc [-10..10]	CD [um]
AZ 1512	1.6	130	-2	2
AZ 1512	1.1	90	-2	1.5
AZ 9260	4	190	2	1.4
AZ 9260	10	350	3	1.6
AZ ECI 3007	0.6	120	-2	1
AZ ECI 3007	1	160	-2	1.2
AZ ECI 3027	2	320	-2	1.4
AZ ECI 3027	4	650	-2	1.4
AZ ECI 3027	5	800	-2	1.5
AZ P4000	5	500	0	2
AZ P4000	10	900	2	3
AZ P4000	20	1800	6	4
ma-P 1205	0.5	110	0	1
ma-P 1205	1	110	0	1
ma-P 1225	2.5	140	0	1.5
ma-P 1225	4.5	200	0	1.5
S1805	0.5	100	0	1
S1805	1	150	-1	1.2
AZ4562	6.2	200	2	1.5
mr-DWL	40	250 – 350	0 – 10	2
mr-DWL	80	300 – 400	0 – 10	3

# Application Note

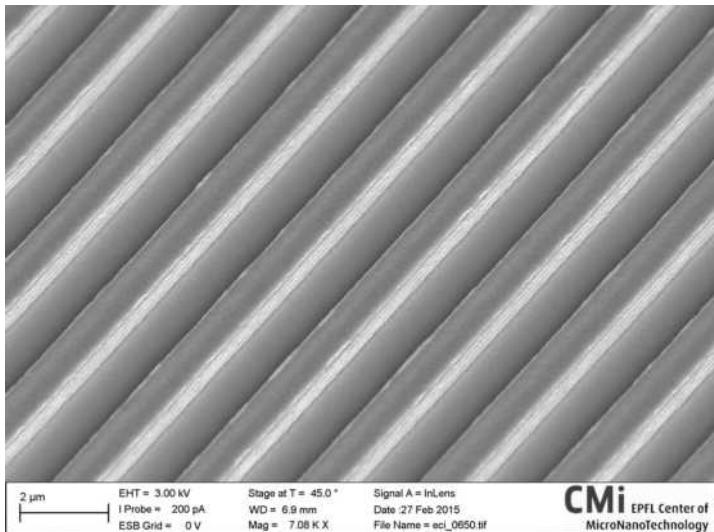


Fig. 1: AZ ECI 3007, 0.6  $\mu\text{m}$  thick, 1.2  $\mu\text{m}$  lines and spaces

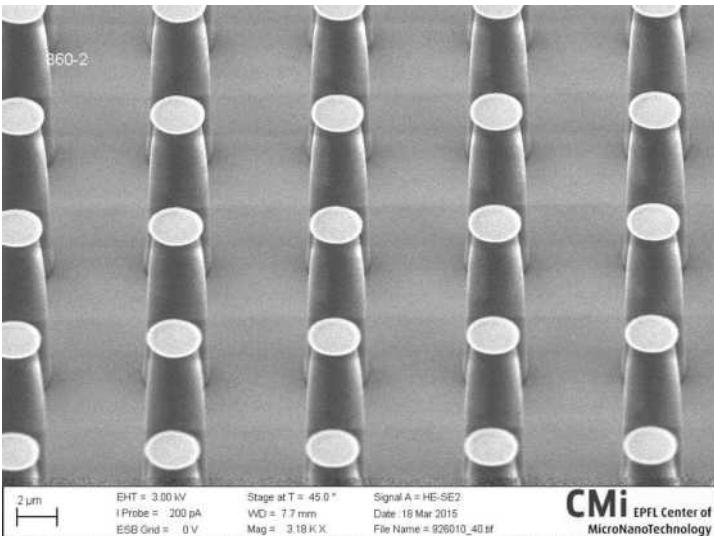


Fig. 2: AZ 9260, 10  $\mu\text{m}$  thick, pillars with a diameter of 4  $\mu\text{m}$

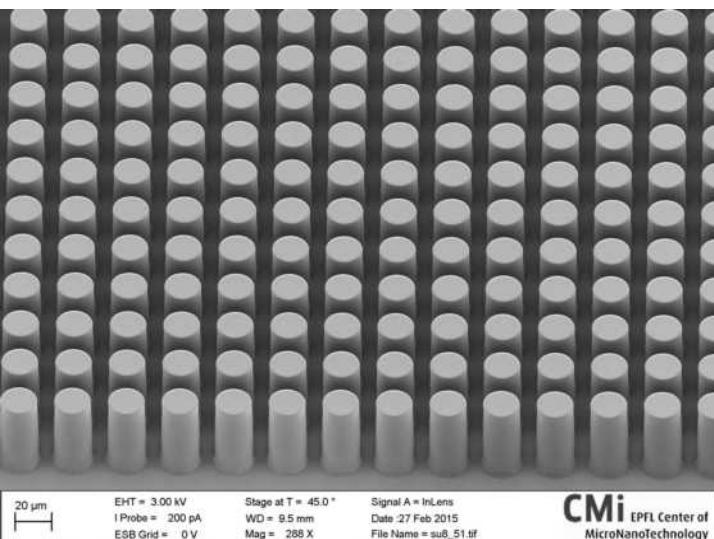


Fig. 3: mr-DWL 40, 40  $\mu\text{m}$  thick, pillars with a diameter of 20  $\mu\text{m}$

# Application Note

## Examples of structures exposed in mr-DWL negative resist:

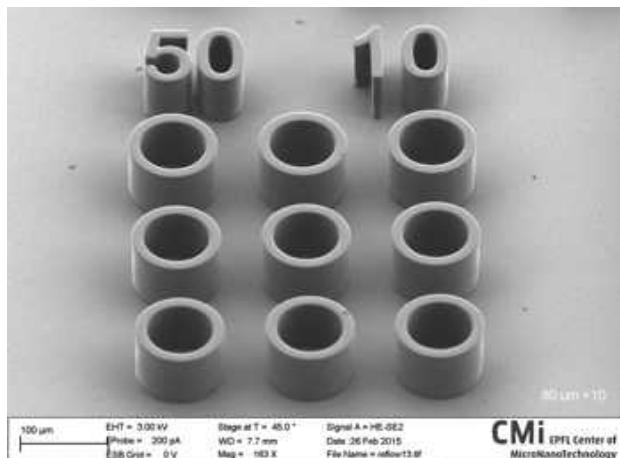


Fig. 4: mr-DWL 40, 80  $\mu\text{m}$  thick, 100  $\mu\text{m}$  wide cylinders with 10  $\mu\text{m}$  wide walls

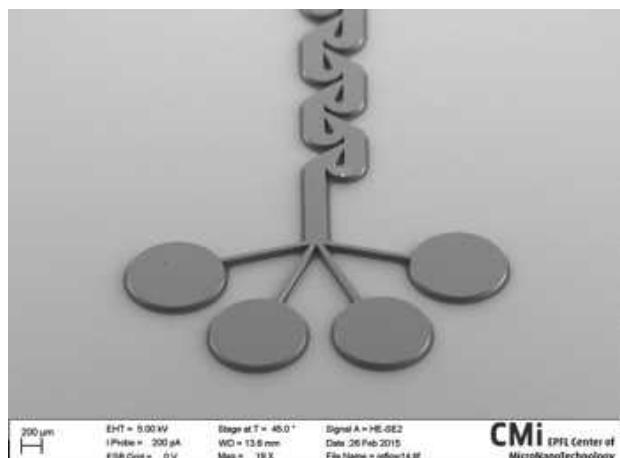


Fig. 5: mr-DWL 40, 80  $\mu\text{m}$  thick, microfluidic device

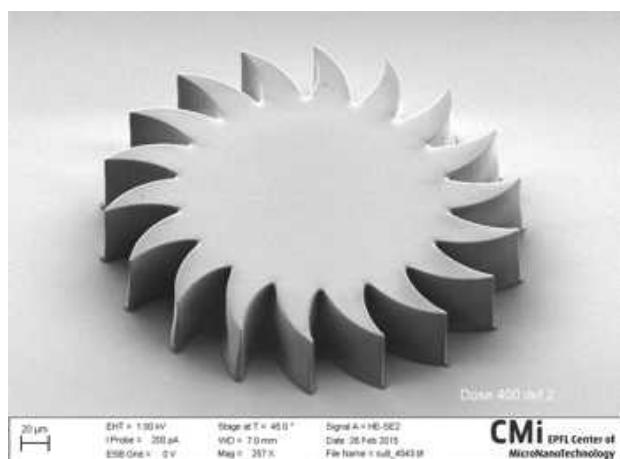


Fig. 6: mr-DWL 40, 40  $\mu\text{m}$  thick, gear wheel

## Examples of structures exposed in mr-DWL thick resist:

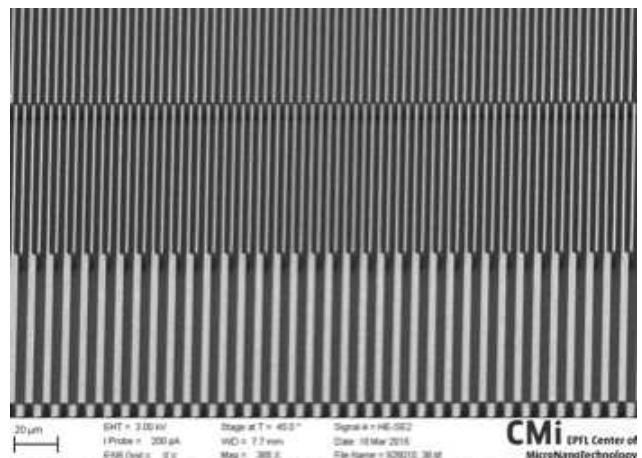


Fig. 7: AZ 9260, 10  $\mu\text{m}$ , 4  $\mu\text{m}$  and 2  $\mu\text{m}$  lines and spaces

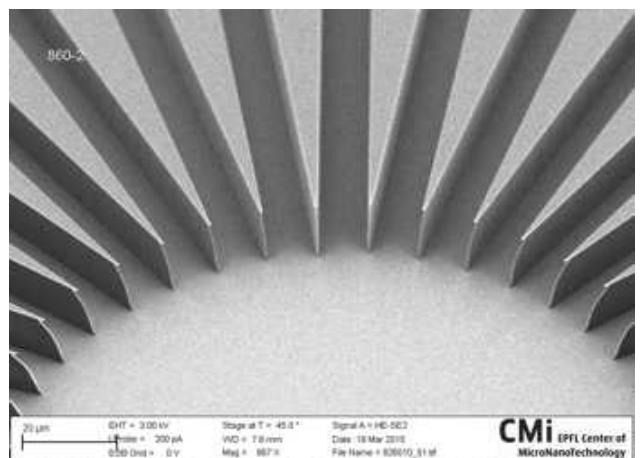


Fig. 8: AZ 9260, 10  $\mu\text{m}$  thick, 10  $\mu\text{m}$  spaces forming an asterisk

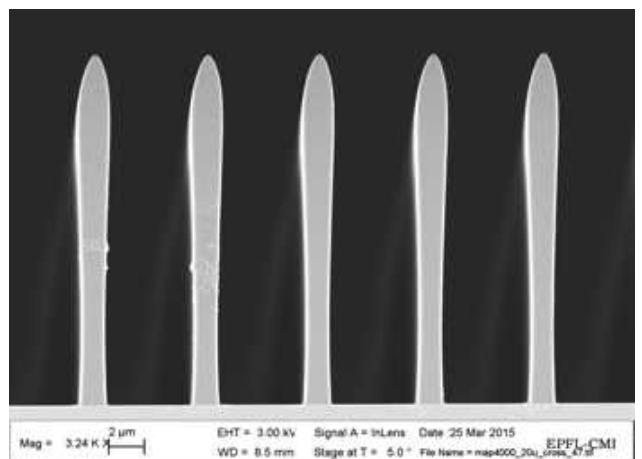


Fig. 9: AZ P4000, 20  $\mu\text{m}$  thick, cross-section of 1.5  $\mu\text{m}$  lines, 4.5  $\mu\text{m}$  spaces

# Application Note

## Examples of structures exposed in thinner positive resists:

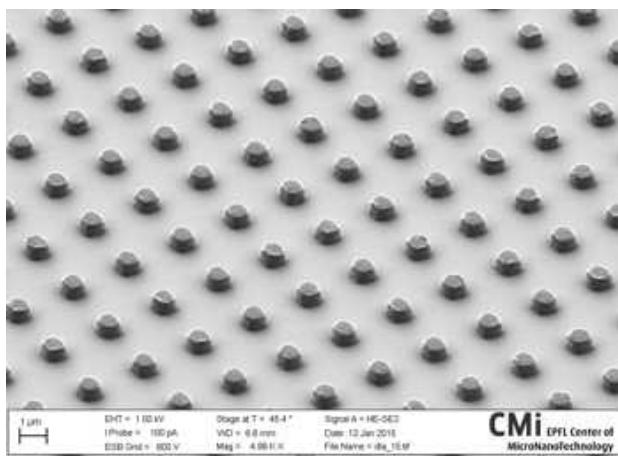


Fig. 10: AZ ECI 3007, 0.6 μm thick, 0.9 μm pillars with 1.5 μm spaces

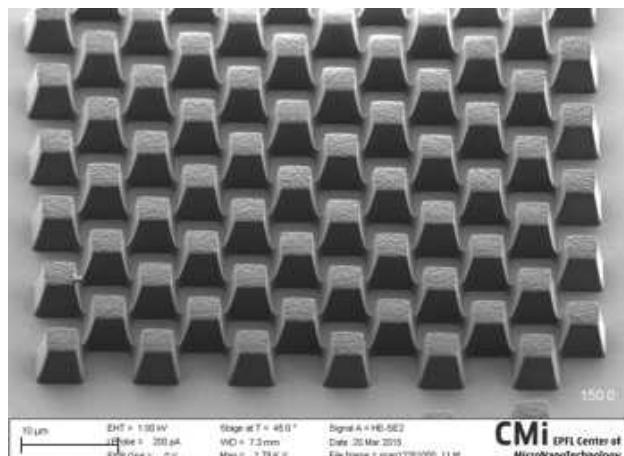


Fig. 13: ma-P 1225, 4.5 μm thick, 5 μm checkerboard

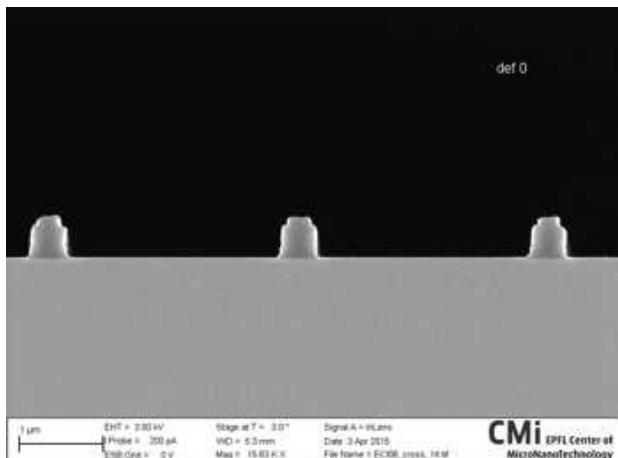


Fig. 11: AZ ECI 1207, 0.6 μm thick, cross-section of 0.5 μm lines with a period of 3 μm

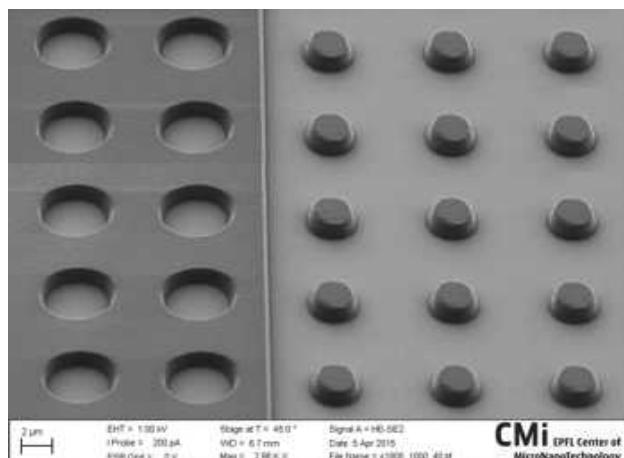


Fig. 14: S1805, 1 μm thick, holes and circles with a radius of 2 μm

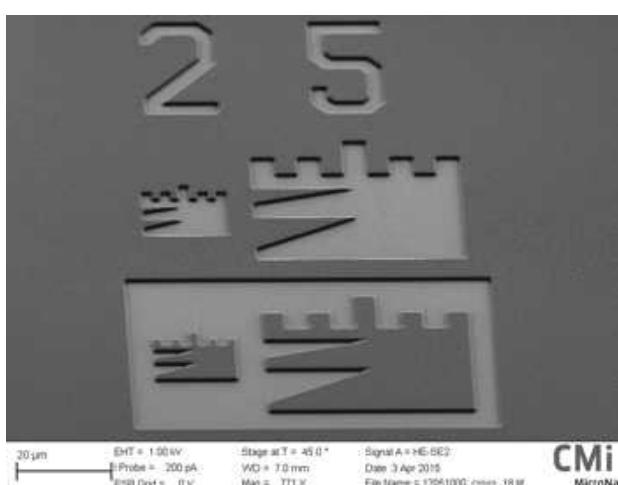


Fig. 12: ma-P 1205, 1 μm thick, resolution test structure

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